



Industrial Computing Platform Partner

AEC-VPMS-200

Environment Test Report

Report NO: 07P020027

Issued by: **Sean Hsu** / **09/26/2007**

Test Engineer Date

Reviewed by: **Wenyuan Yang** / **09/26/2007**

Manager Date

Test item list

1. <i>Test item list</i> -----	2
2. <i>Temperature cycle operation test</i> -----	3~6
3. <i>High temperature storage test</i> -----	7
4. <i>Low temperature storage test</i> -----	8
5. <i>Humidity test</i> -----	9
6. <i>Cold start and hot start test</i> -----	10

Num	Item	Spec
1.	Power management Module	AEC-VPMS-200 REV 0.2

Inside



Temperature cycle test

Test Date: 09-03~05-2007

Test Product: AEC-VPMS-200

Test Site: AAEON QA Internal Lab.

Test Standard: Reference IEC68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

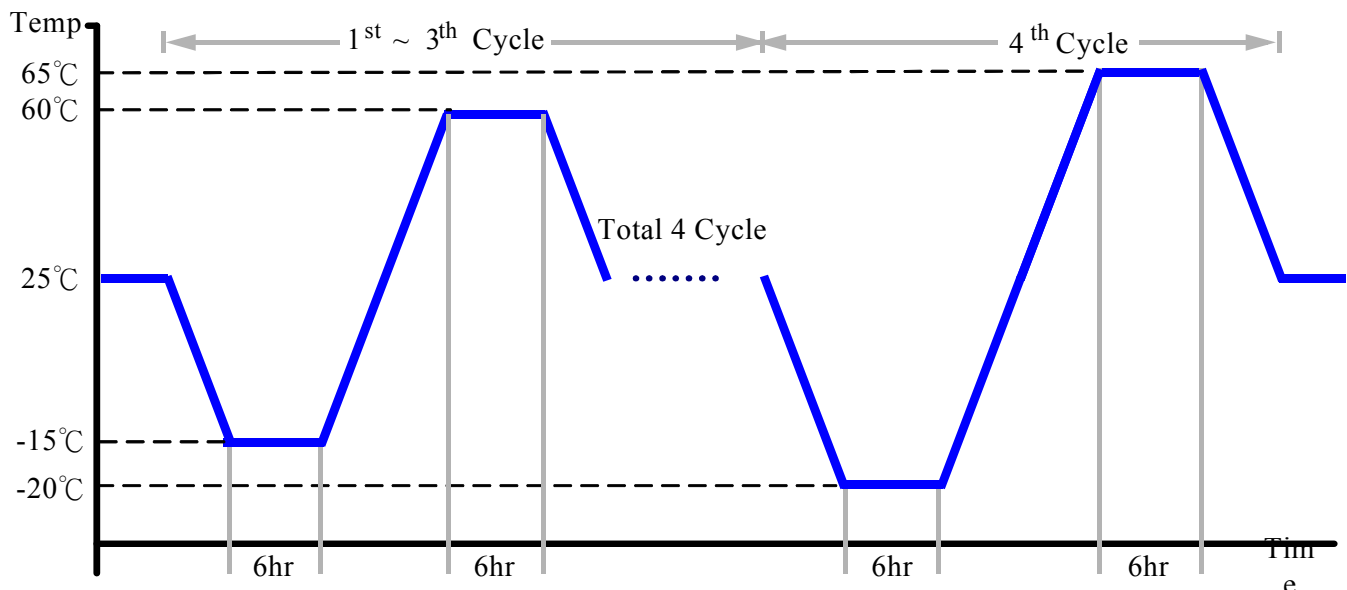
Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-A4C-100
Date of Calibration: 07/07/06
Serial Number: 3188

Temperature Measurement:

40 Channel Thermal Recorder:
YOKOGAWA Inc,
Model: DA100-13-1D
Date of Calibration: 12/11/06
Serial Number: 12A323190

Test Condition:

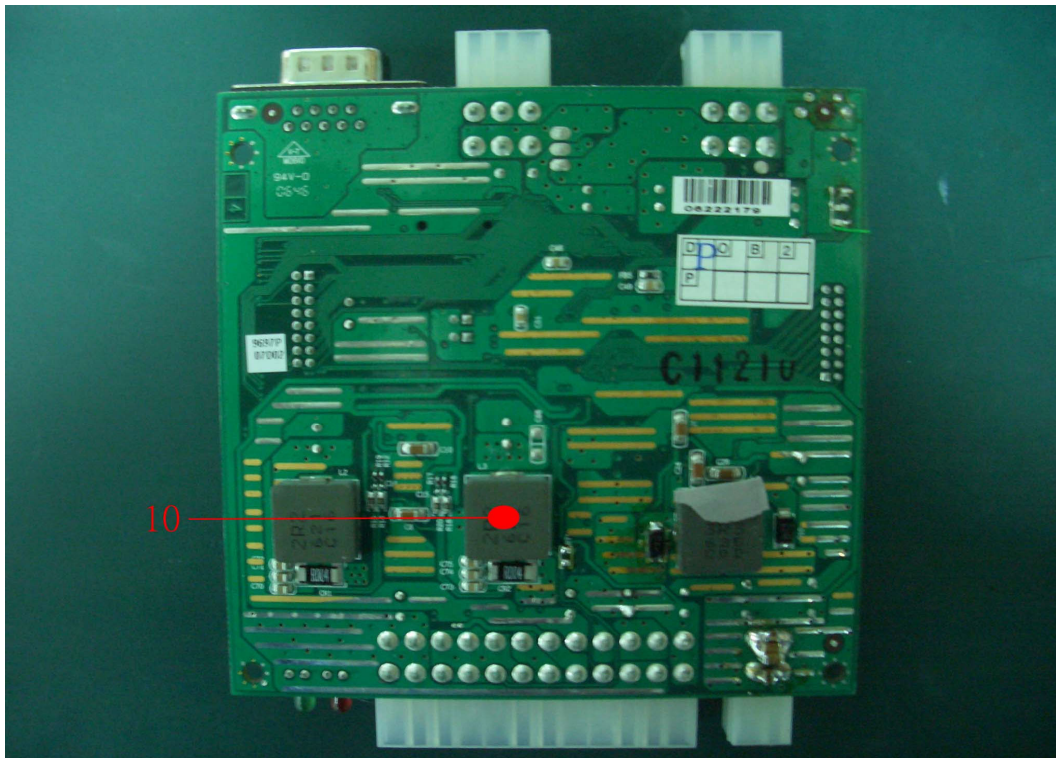
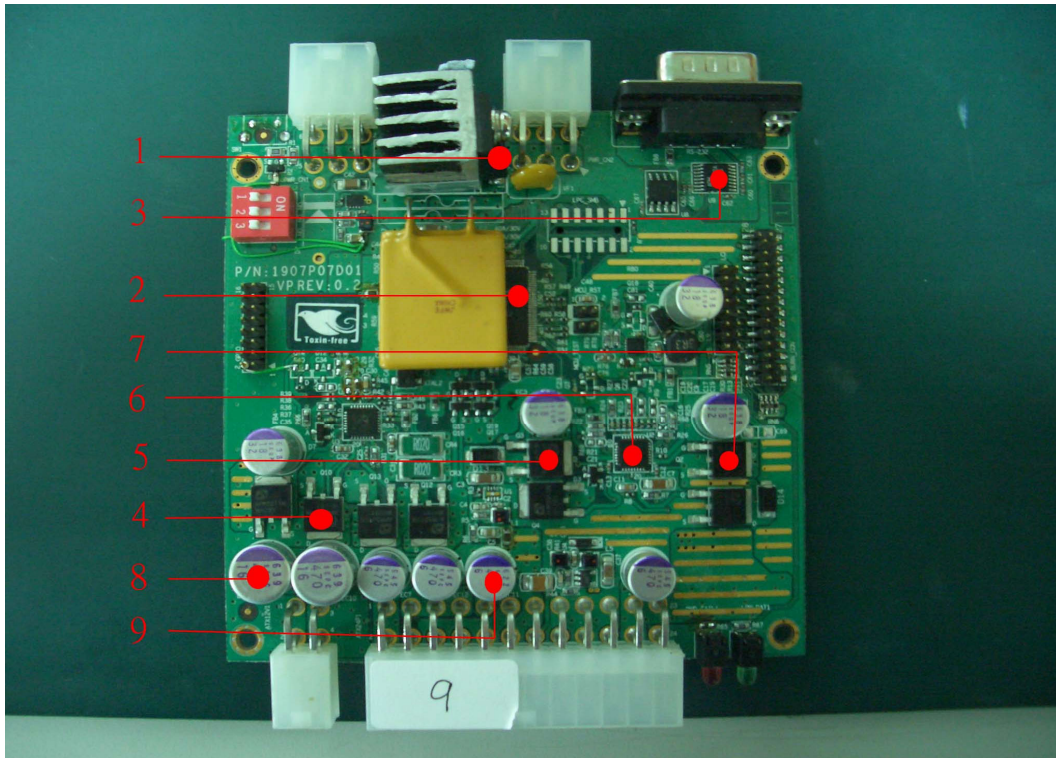
1. Test Low Temperature: -15°C (1~3 cycle)
-20°C (4th cycle)
2. Test High Temperature: 60°C (1~3 cycle)
65°C (4th cycle)
3. Test dwell time: 6Hrs
4. Temperature slope: 2°C/min
5. Test cycle: 4 cycle
6. Test Environment Curve:



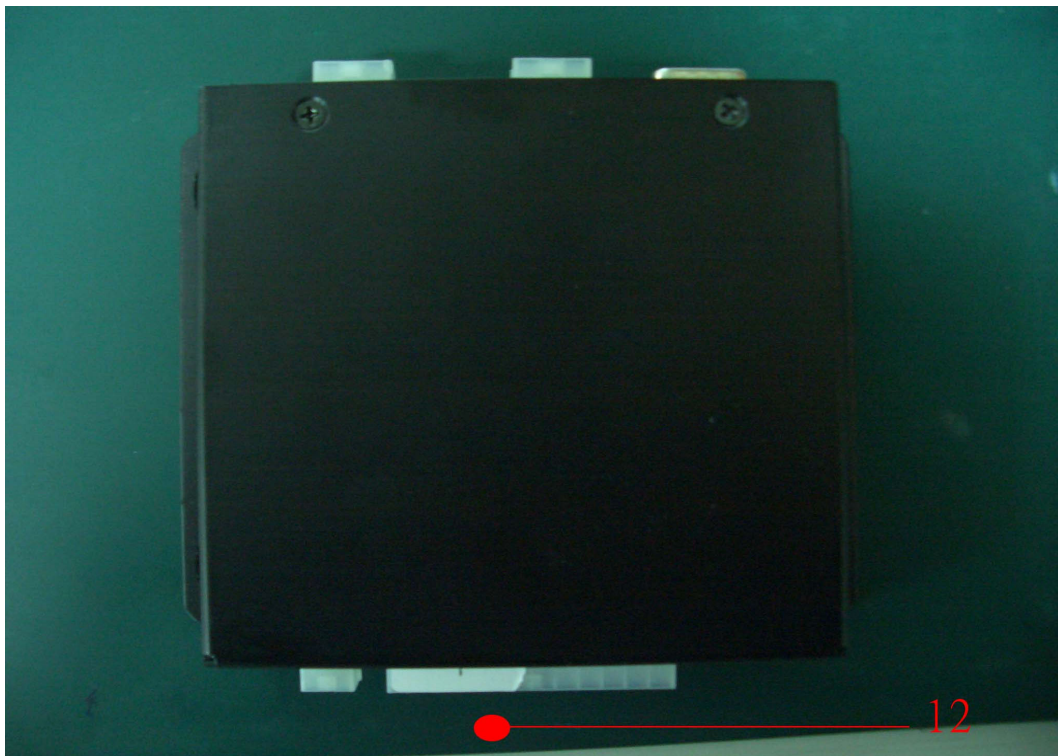
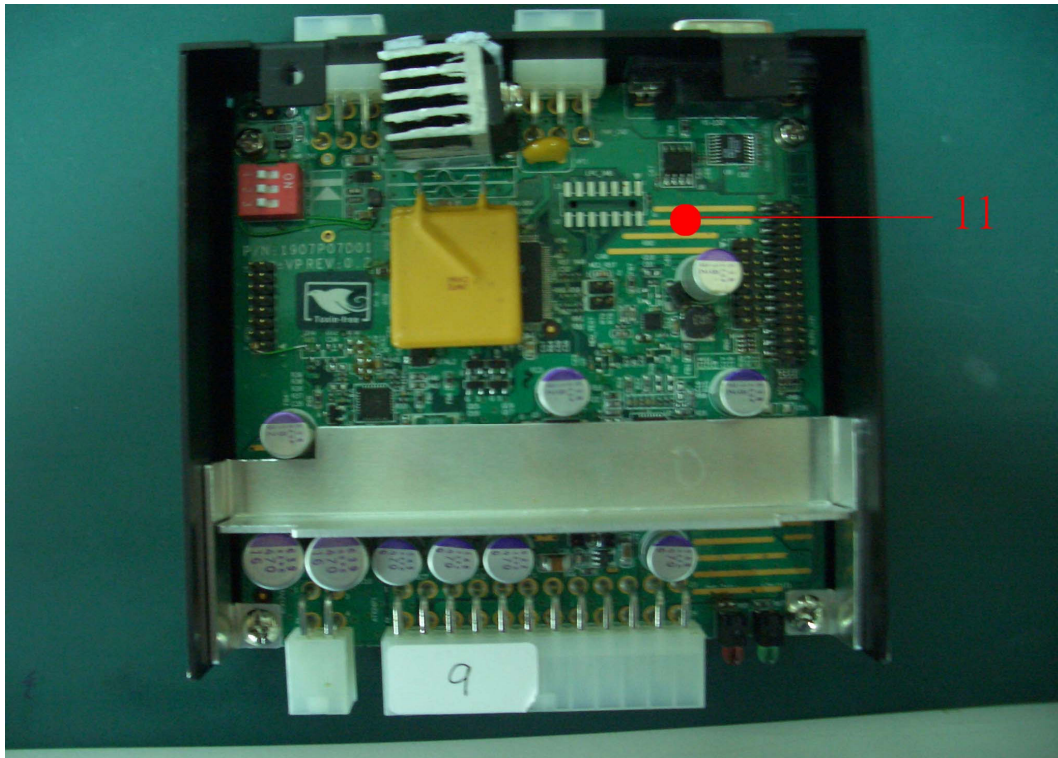
Temperature cycle test

Temperature Recorder:

Measuring Thermal Couple Position:



Temperature cycle test



Temperature cycle test

Thermal profile data:

AEC-VPMS-200

Point	Temp. Stage(°C)	Spec	60	25	-15
1. D1-(TF)D.Schottky.20A.TO-220F.DIP.Fairchild.FYPF2010DNTU		125	113.9	78.9	43.9
2. U6-(TF)IC.SMD.LQFP.128Pin.Embedded Controller.Winbond.W83L951DG		95	95.6	60.6	25.6
3. U9-(TF) IC.SMD.TSSOP16.RS232 Transceivers.460Kbitsw/1.		85	81.9	46.9	11.9
4. Q10-(TF)PWR.SMD.TO-252.N-Channel.Mosfet.Vds=30V Ids=40A		150	99	64.0	29.0
5. Q3-(TF)PWR.SMD.TO-252.N-Channel.Mosfet.Vds=30V Ids=40A		150	91.9	56.9	21.9
6. U2-(TF)IC.SMD.QFN 32Pin Regulator.Vin 3.5-36V.LINEAR.		85	89.3	54.3	19.3
7. Q2-(TF)PWR.SMD.TO-252.N-Channel.Mosfet.Vds=30V Ids=40A		150	88.2	53.2	18.2
8. EC9-(TF)OS-CON.470UF.16V.20%.DIP.10*13mm.SANYO.16SEPC470M		105	93.3	58.3	23.3
9. EC11-(TF)OS-CON.470uF.6.3V.20%.		105	92.2	57.2	22.2
10.L3- (TF)COIL.2.2uH.SMD.13.8*12.8*5.0mm.		125	92.1	57.1	22.1
11. Control Box Internal inside Air Temperature		N/A	80.1	45.1	10.1
12 Chamber Air Temperature		N/A	60.9	25.9	-9.1

Sample Configuration & Quantity Under Test:

Quantity: 1 (AEC-VPMS-200)

Test Result:

No problem was found during the temperature operation cycle test.

High temperature storage test

Test Date: 08-27~29-2007

Test Product: AEC-VPMS-200

Test Site: AAEON QA Internal Lab.

Test Standard: Reference IEC 68-2-2 Testing procedures
Test Bb: Dry Heat Test (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.

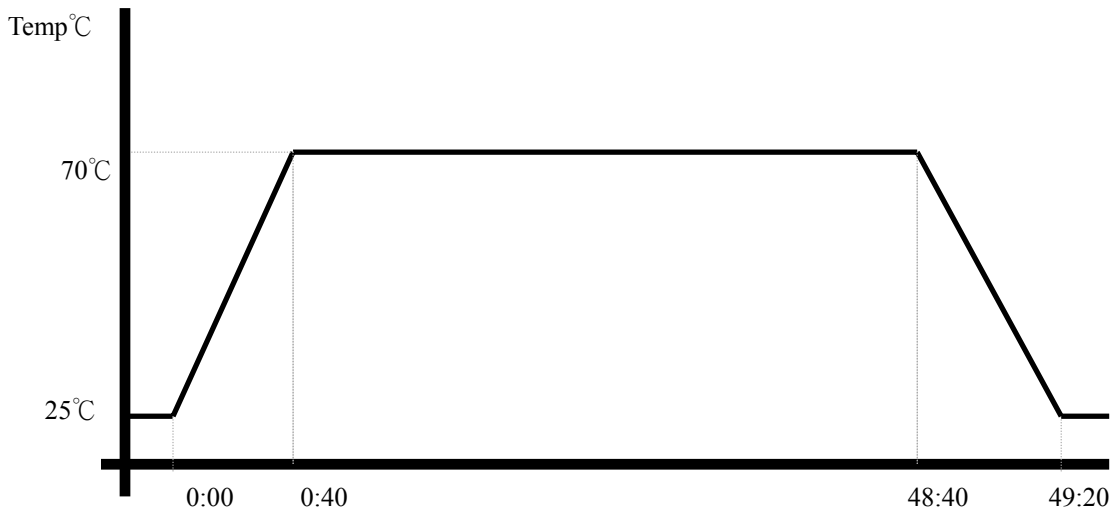
Model: THS-A4C-100

Date of Calibration: 07/07/06

Serial Number: 3188

Testing Item:

1. Test Temperature: 70°C
2. Test Times: 48Hrs
3. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (AEC-VPMS-200)

Test Result:

No problem was found after the high temperature storage test.

Test Date: 08-30~31-2007

Test Product: AEC-VPMS-200

Test Site: AAEON QA Internal Lab.

Test Standard: Reference IEC 68-2-1
Testing procedures Test Ab: Cold Test (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber

K.SON. INS. TECH. CORP.

Model: THS-A4C-100

Date of Calibration: 07/07/06

Serial Number: 3188

Testing Item:

1. Test Temperature: -20°C
2. Test Times: 48Hrs
3. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (AEC-VPMS-200)

Test Result:

No problem was found after the low temperature storage test.

Test Date: 09-01~03-2007

Test Product: AEC-VPMS-200

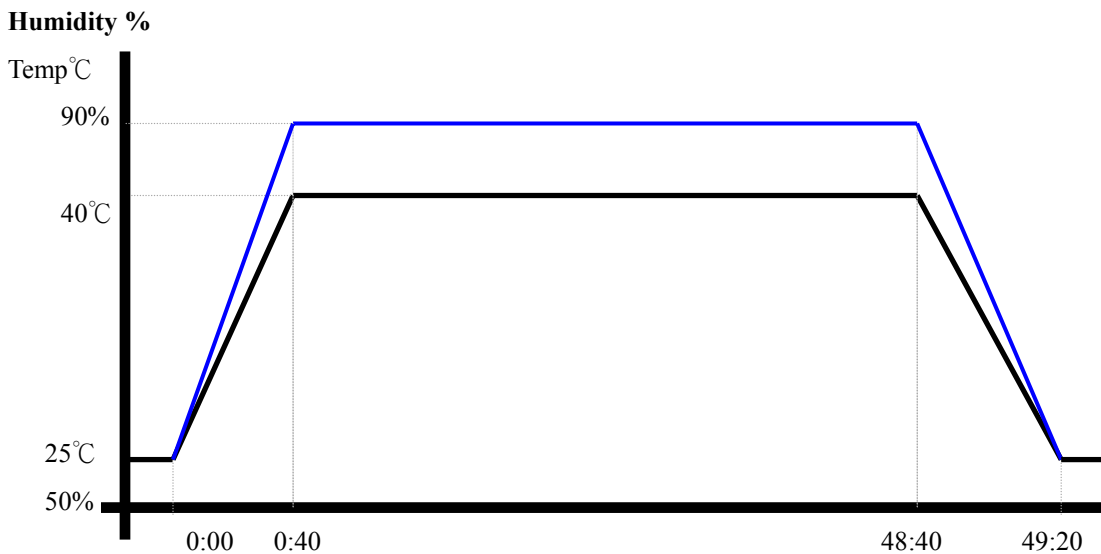
Test Site: AAEON QA Internal Lab.

Test Standard: Reference IEC 68-2-3 Testing procedures
Test Ca: Damp heat, steady state (Non-operation)

Test Equipment:
Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-A4C-100
Date of Calibration: 07/07/06
Serial Number: 3188

Testing Item:

1. Test Temperature: 40°C
2. Test Humidity: 90%RH
3. Test Times: 48Hrs
4. Test Environment Curve:



Sample Configuration & Quantity Under Test:
Quantity: 1 (AEC-VPMS-200)

Test Result:
No problem was found after the humidity storage test.

Cold start and hot start test

Test Date: 08-23~24-2007

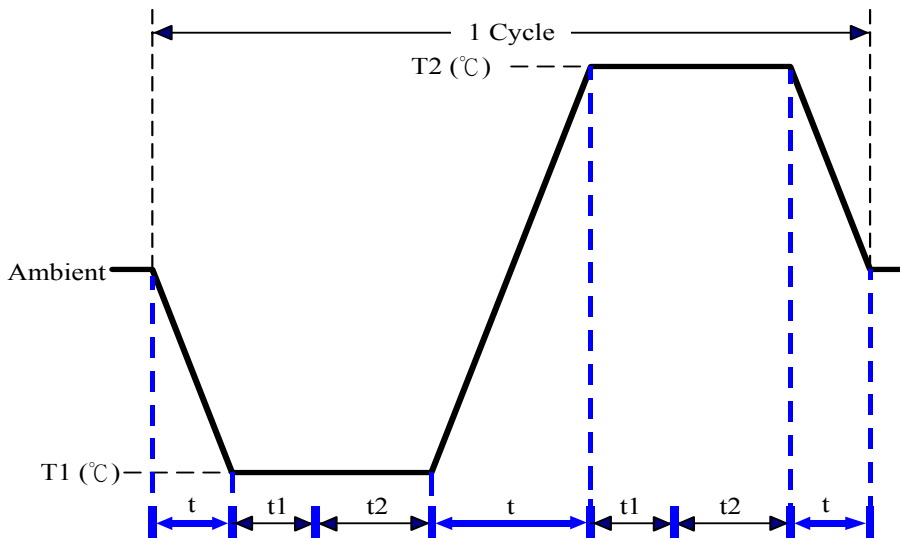
Test Product: AEC-VPMS-200

Test Site: AAEON QA Internal Lab.

Test Standard: Reference IEC 68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:
Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-A4C-100
Date of Calibration: 07/07/06
Serial Number: 3188

Test Condition:



Parameters	Description
T1	-20°C
T2	65°C
t1	1 hrs
t2	2 hrs
t	2°C/min
n (Cycle)	1

t = temperature slope
t ~ t1: Power Off
t2: Power on/off test 10 times (on 2 min / off 5min)

Test Result:

- No problem was found during the cold start test.
- No problem was found during the hot start test.